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Patent Application

Inventor(s):

Ho-Yuan Yu

Application No.:

10/816,980

Group Art Unit:

Filed:

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Examiner:

Title:

METHOD AND STRUCTURE FOR COMPOSITE TRENCH FILL

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U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub- class	Filing Date
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Foreign Patent or Published Foreign Patent Application

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Examiner	1	Document	Publication	Country or		Sub-	Trans	lation
Initial	No.	No	Date	Patent Office	Class	class	Yes	No
	В							

Other Documents

Examiner						
Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication				
MA	С	H. Ogiwara, M. Hayakawa, T. Nishimura and M. Nakaoka; "HIGH-FREQUENCY INDUCTION HEATING INVERTER WITH MULTI-RESONANT MODE USING NEWLY DEVELOPED NORMALLY-OFF TYPE STATIC INDUCTION TRANSISTORS"; Department of Electrical Engineering, Ashikaga Institute of Technology, Japan; Department of Electrical Engineering, Oita University, Japan; Department of Electrical Engineering, Kobe University, Japan; pages 1017-1023				
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Examiner	NN	Date Considered 4 14-03				

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.